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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application Of — David B. Thomas

Weng Chang — Patent Examiner

Application No: 10/684,288 — Art Unit 3723

Filed: 10/08/2003

Title: Methods for Enhancing Within-Wafer CMP Uniformity

Attorney Docket No: 67,200-1020

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Certificate of Mailing

I hereby certify that this paper (along with any referred to as being attached or enclosed) is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Date: 12/27, 2004

~~Kathy Dixon~~ R. TUNG

RESPONSE TO OFFICE ACTION

Applicants respond to the Office action dated August 26, 2004, in the following manner.